

Notice of References Cited	Application/Control No. 10/800,219		Applicant(s)/Patent Under Reexamination STRELKOVA ET AL.	
	Examiner Nelson Lam		Art Unit 2825	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,658,640	12-2003	Weed, J. Tracy	716/19
*	B	US-6,421,820	07-2002	Mansfield et al.	716/21
*	C	US-6,562,638	05-2003	Balasinski et al.	438/14
*	D	US-2004/0170905	09-2004	Liebmann et al.	430/005
*	E	US-6,602,728	08-2003	Liebmann et al.	438/16
*	F	US-6,470,489	10-2002	Chang et al.	716/21
*	G	US-6,513,151	01-2003	Erhardt et al.	716/21
*	H	US-2004/0123264	06-2004	Tsai et al.	716/019
*	I	US-6,751,519	06-2004	Satya et al.	700/121
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Layout Printability Optimization using a Silicon Simulation Methodology", IEEE Computer Society, 2004, Michel Cote, Philippe Hurat.
	V	"Advanced Physical Models for Mask Data Verification and Impacts on Physical Layout Synthesis", IEEE Computer Society, Proceedings of the Fourth International Symposium on Quality Electroic Design, 2003, Qi-De Qian, Sheldon X.-D. Tan.
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.